

OptiMOS™ 2 Small-Signal-Transistor

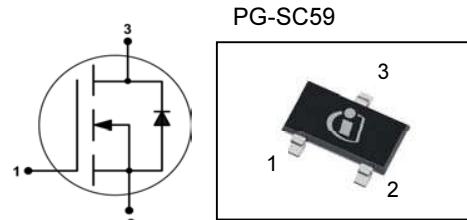
Features

- N-channel
- Enhancement mode
- Ultra Logic level (1.8V rated)
- Avalanche rated
- Footprint compatible to SOT23
- Qualified according to AEC Q101
- 100% lead-free; RoHS compliant



Product Summary

| | | |
|------------------|-----------------------|----|
| V_{DS} | 20 | V |
| $R_{DS(on),max}$ | $V_{GS}=2.5\text{ V}$ | 23 |
| | $V_{GS}=1.8\text{ V}$ | 32 |
| I_D | 3.7 | A |



| Type | Package | Tape and Reel Information | Marking | Lead Free | Packing |
|---------|---------|---------------------------|---------|-----------|---------|
| BSR802N | PG-SC59 | L6327 = 3000 pcs. / reel | LFs | Yes | Non dry |

Maximum ratings, at $T_j=25\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Value | Unit |
|-------------------------------------|----------------|---|----------------------|------------------|
| Continuous drain current | I_D | $T_A=25\text{ }^\circ\text{C}$ | 3.7 | A |
| | | $T_A=25\text{ }^\circ\text{C}$ | 2.9 | |
| Pulsed drain current | $I_{D,pulse}$ | $T_A=70\text{ }^\circ\text{C}$ | 14.8 | |
| Avalanche energy, single pulse | E_{AS} | $I_D=3.8\text{ A}, R_{GS}=25\text{ }\Omega$ | 30 | mJ |
| Reverse diode dv/dt | dv/dt | $I_D=3.8\text{ A}, V_{DS}=16\text{ V}, di/dt=200\text{ A}/\mu\text{s}, T_{j,max}=150\text{ }^\circ\text{C}$ | 6 | kV/ μ s |
| Gate source voltage | V_{GS} | | ± 8 | V |
| Power dissipation ¹⁾ | P_{tot} | $T_A=25\text{ }^\circ\text{C}$ | 0.5 | W |
| Operating and storage temperature | T_j, T_{stg} | | -55 ... 150 | $^\circ\text{C}$ |
| ESD Class | | JESD22-A114-HBM | 0 (<250V) | |
| Soldering Temperature | | | 260 $^\circ\text{C}$ | |
| IEC climatic category; DIN IEC 68-1 | | | 55/150/56 | |

| Parameter | Symbol | Conditions | Values | | | Unit |
|--|-----------------------------|--|--------|------|------|------------------|
| | | | min. | typ. | max. | |
| Thermal characteristics | | | | | | |
| Thermal resistance, junction - ambient | R_{thJA} | minimal footprint ¹⁾ | - | - | 250 | K/W |
| Electrical characteristics , at $T_j=25^\circ\text{C}$, unless otherwise specified | | | | | | |
| Static characteristics | | | | | | |
| Drain-source breakdown voltage | $V_{(\text{BR})\text{DSS}}$ | $V_{\text{GS}}=0\text{ V}, I_D=250\text{ }\mu\text{A}$ | 20 | - | - | V |
| Gate threshold voltage | $V_{\text{GS}(\text{th})}$ | $V_{\text{DS}}=V_{\text{GS}}, I_D=30\text{ }\mu\text{A}$ | 0.3 | 0.55 | 0.75 | |
| Drain-source leakage current | I_{DSS} | $V_{\text{DS}}=20\text{ V}, V_{\text{GS}}=0\text{ V}, T_j=25^\circ\text{C}$ | - | - | 1 | μA |
| | | $V_{\text{DS}}=20\text{ V}, V_{\text{GS}}=0\text{ V}, T_j=150^\circ\text{C}$ | - | - | 100 | |
| Gate-source leakage current | I_{GSS} | $V_{\text{GS}}=8\text{ V}, V_{\text{DS}}=0\text{ V}$ | - | - | 100 | nA |
| Drain-source on-state resistance | $R_{\text{DS}(\text{on})}$ | $V_{\text{GS}}=1.8\text{ V}, I_D=3.2\text{ A}$ | - | 22 | 32 | $\text{m}\Omega$ |
| | | $V_{\text{GS}}=2.5\text{ V}, I_D=3.7\text{ A}$ | - | 17 | 23 | |
| Transconductance | g_{fs} | $ V_{\text{DS}} >2 I_D R_{\text{DS}(\text{on})\text{max}}, I_D=2.9\text{ A}$ | | 16 | - | S |

¹⁾ Performed on 40mm² FR4 PCB. The traces are 1mm wide, 70μm thick and 20mm long; they are present on both sides of the PCB.

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Dynamic characteristics

| | | | | | | |
|------------------------------|--------------|--|---|------|------|----|
| Input capacitance | C_{iss} | $V_{GS}=0 \text{ V}, V_{DS}=10 \text{ V}, f=1 \text{ MHz}$ | - | 1013 | 1447 | pF |
| Output capacitance | C_{oss} | | - | 290 | 414 | |
| Reverse transfer capacitance | C_{rss} | | - | 51 | 73.0 | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD}=10 \text{ V}, V_{GS}=2.5 \text{ V}, I_D=3.7 \text{ A}, R_G=6 \Omega$ | - | 9.8 | - | ns |
| Rise time | t_r | | - | 18 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 26 | - | |
| Fall time | t_f | | - | 4.1 | - | |

Gate Charge Characteristics

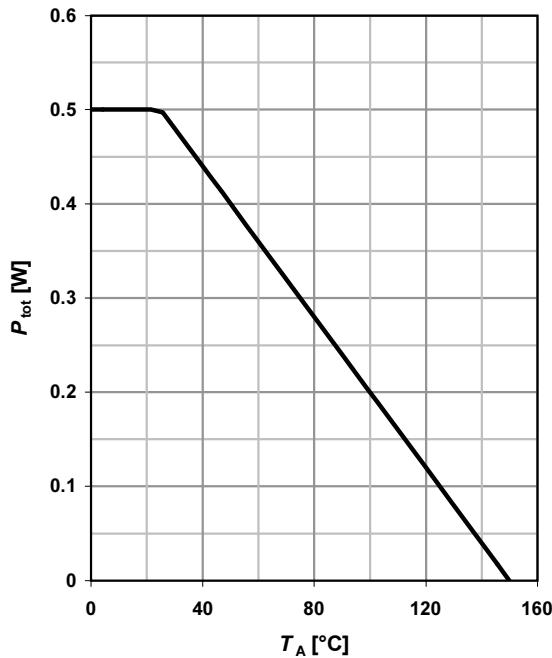
| | | | | | | |
|-----------------------|---------------|--|---|-----|---|----|
| Gate to source charge | Q_{gs} | $V_{DD}=10 \text{ V}, I_D=3.7 \text{ A}, V_{GS}=0 \text{ to } 2.5 \text{ V}$ | - | 1.4 | - | nC |
| Gate to drain charge | Q_{gd} | | - | 1.5 | - | |
| Gate charge total | Q_g | | - | 4.7 | - | |
| Gate plateau voltage | $V_{plateau}$ | | - | 1.4 | - | |

Reverse Diode

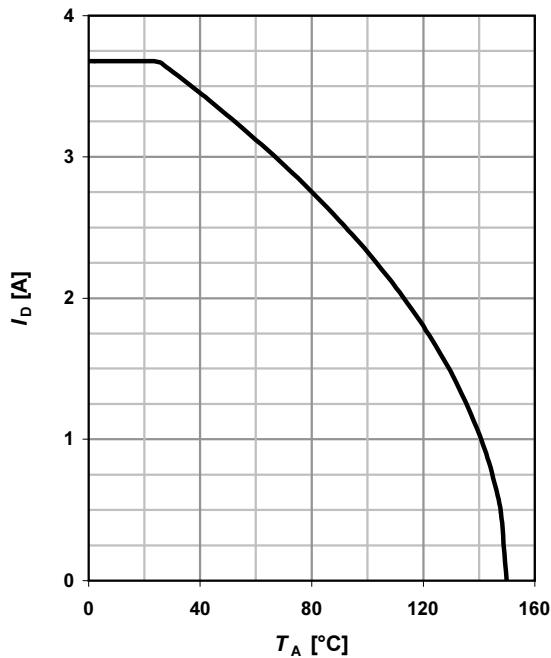
| | | | | | | |
|----------------------------------|---------------|--|---|------|-----|----|
| Diode continuous forward current | I_s | $T_A=25 \text{ }^\circ\text{C}$ | - | - | 0.5 | A |
| Diode pulse current | $I_{s,pulse}$ | | - | - | 15 | |
| Diode forward voltage | V_{SD} | $V_{GS}=0 \text{ V}, I_F=3.7 \text{ A}, T_j=25 \text{ }^\circ\text{C}$ | - | 0.78 | 1.1 | V |
| Reverse recovery time | t_{rr} | $V_R=10 \text{ V}, I_F=3.7 \text{ A}, di_F/dt=100 \text{ A}/\mu\text{s}$ | - | 15 | - | ns |
| Reverse recovery charge | Q_{rr} | | - | 5.2 | - | |

1 Power dissipation

$$P_{\text{tot}} = f(T_A)$$

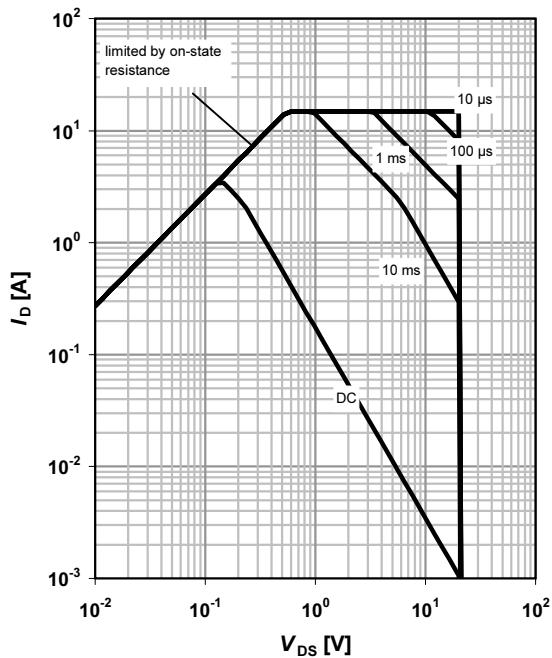

2 Drain current

$$I_D = f(T_A); V_{GS} \geq 2.5 \text{ V}$$


3 Safe operating area

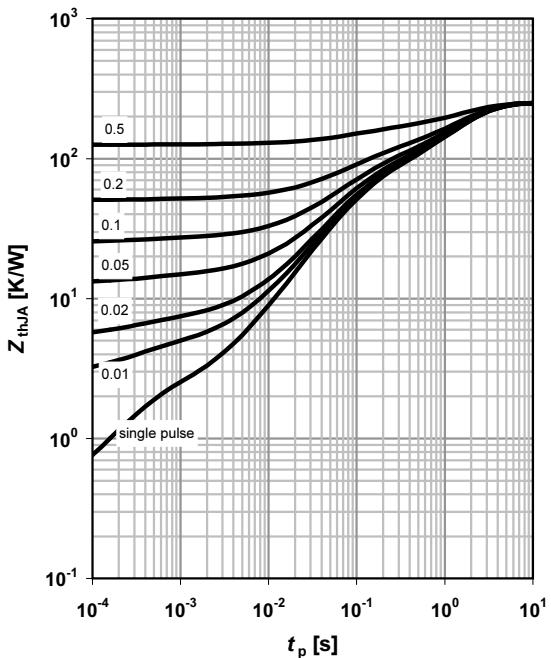
$$I_D = f(V_{DS}); T_A = 25 \text{ °C}; D = 0$$

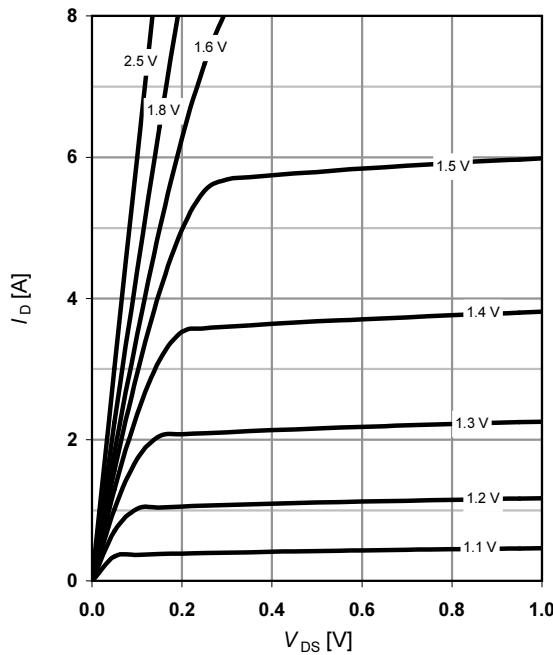
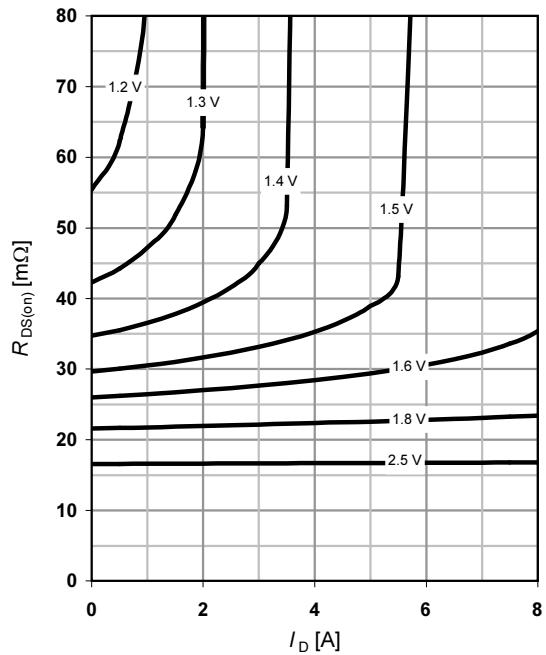
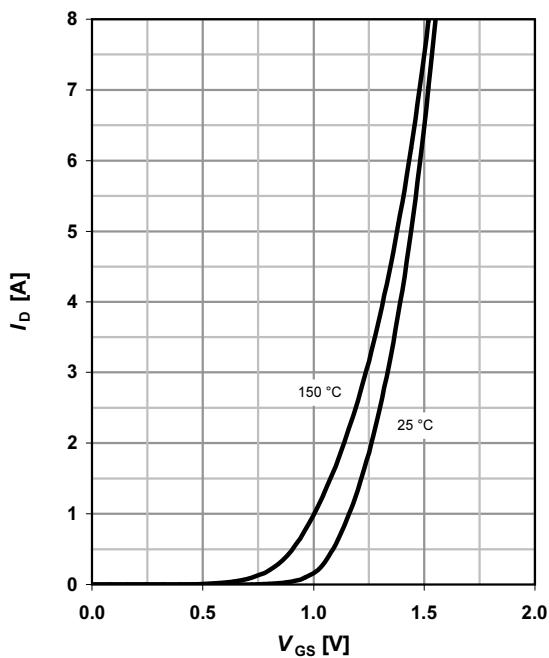
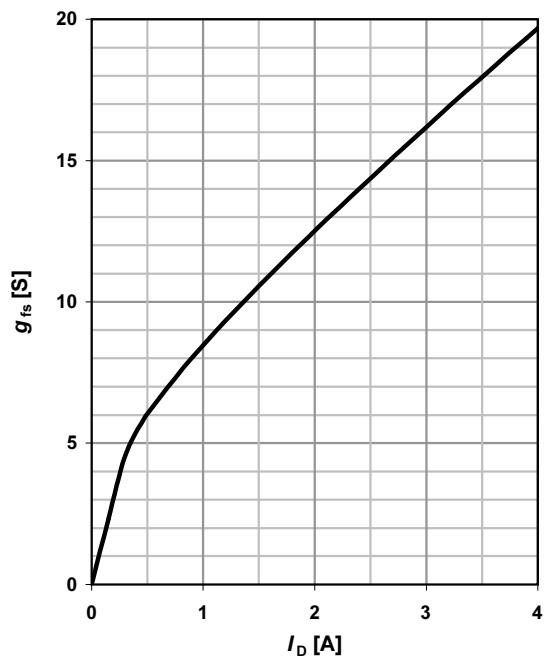
parameter: t_p

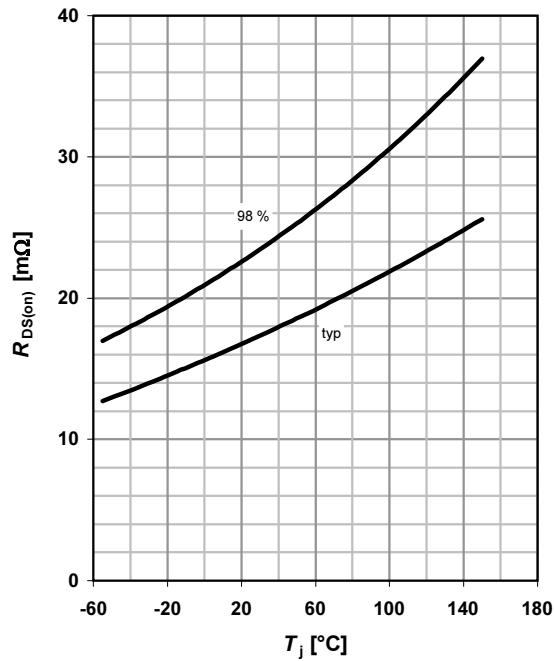

4 Max. transient thermal impedance

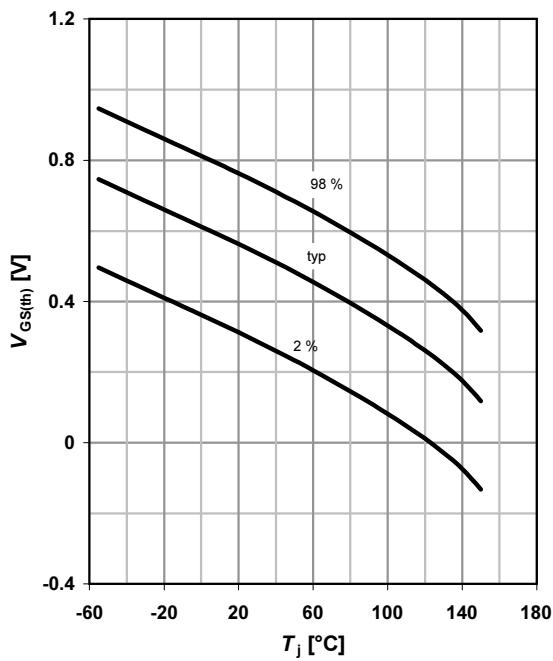
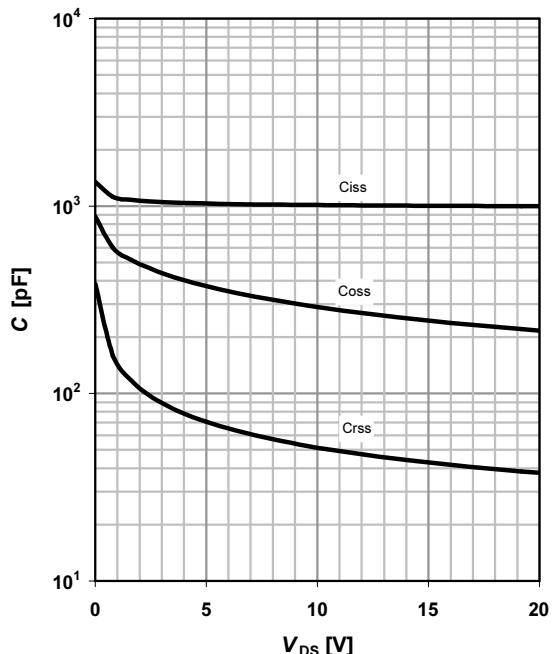
$$Z_{thJA} = f(t_p)$$

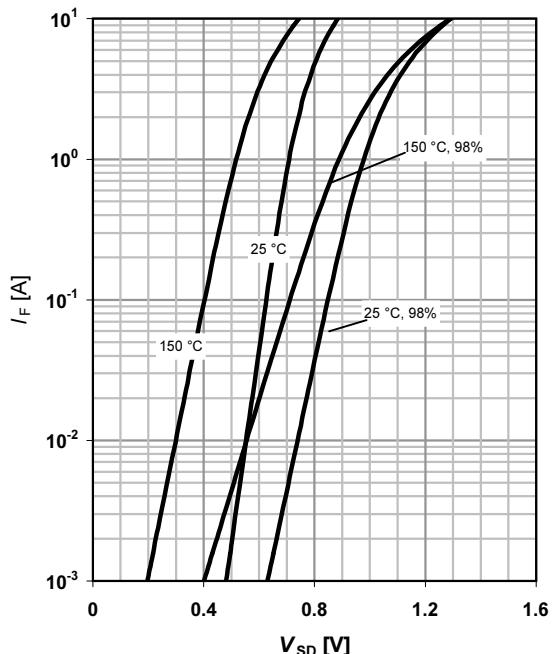
parameter: $D = t_p/T$



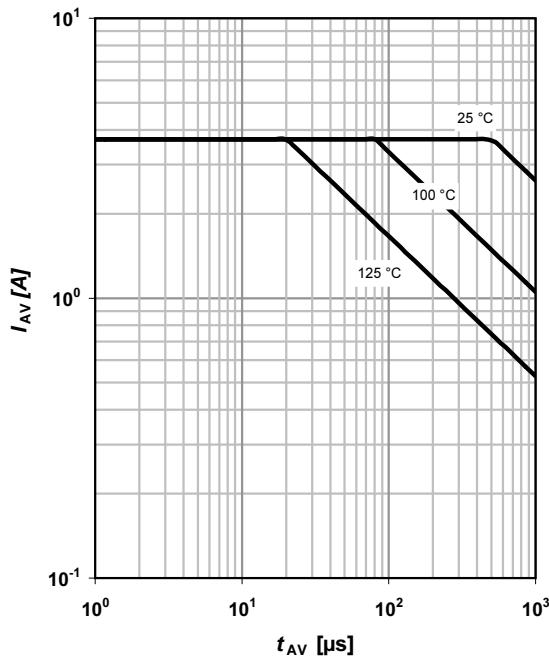
5 Typ. output characteristics
 $I_D = f(V_{DS})$; $T_j = 25^\circ\text{C}$
parameter: V_{GS} 
6 Typ. drain-source on resistance
 $R_{DS(on)} = f(I_D)$; $T_j = 25^\circ\text{C}$
parameter: V_{GS} 
7 Typ. transfer characteristics
 $I_D = f(V_{GS})$; $|V_{DS}| > 2|I_D|R_{DS(on)max}$

8 Typ. forward transconductance
 $g_{fs} = f(I_D)$; $T_j = 25^\circ\text{C}$


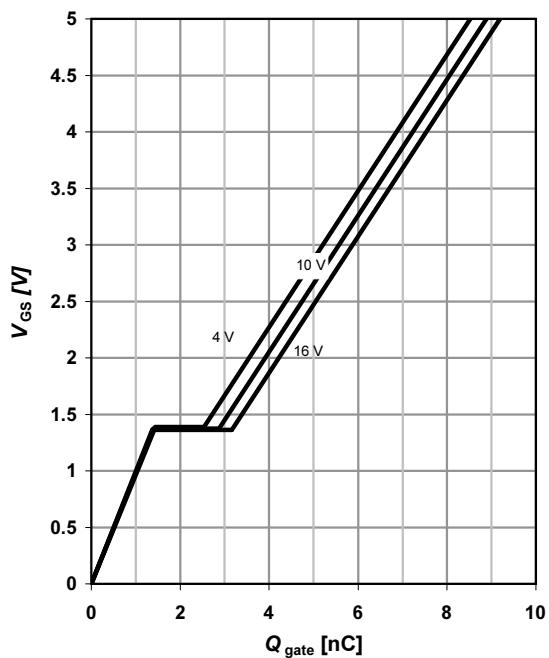
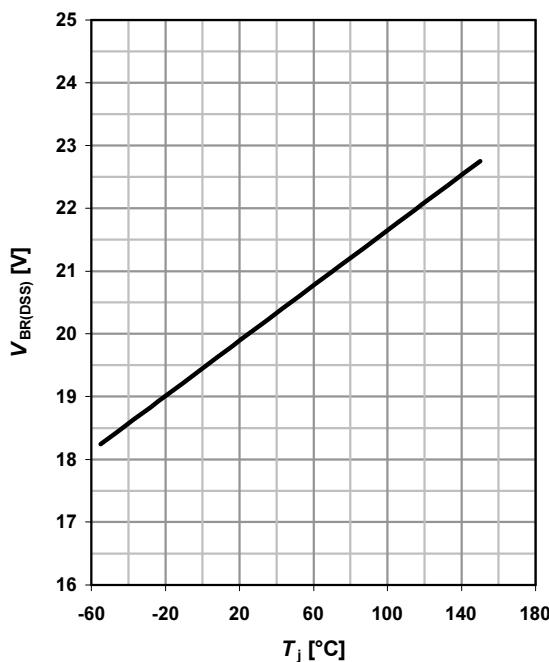
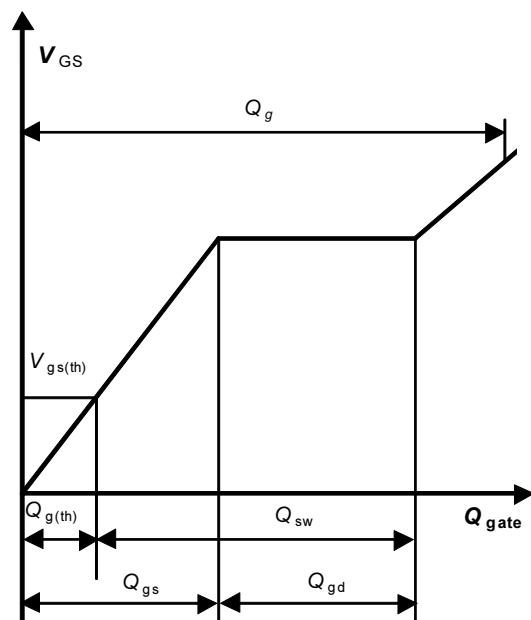
9 Drain-source on-state resistance
 $R_{DS(on)} = f(T_j); I_D = 3.7 \text{ A}; V_{GS} = 2.5 \text{ V}$

10 Typ. gate threshold voltage
 $V_{GS(th)} = f(T_j); V_{DS} = V_{GS}; I_D = 30 \mu\text{A}$

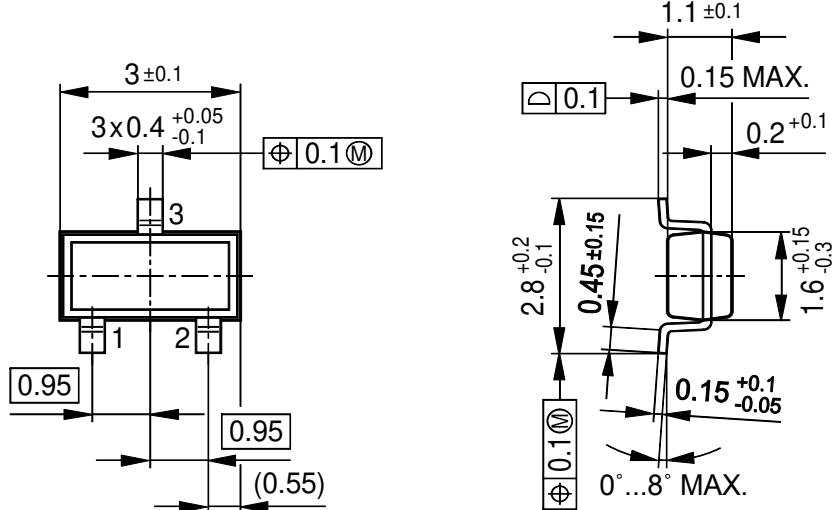
 parameter: I_D

11 Typ. capacitances
 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}; T_j = 25^\circ\text{C}$

12 Forward characteristics of reverse diode
 $I_F = f(V_{SD})$

 parameter: T_j


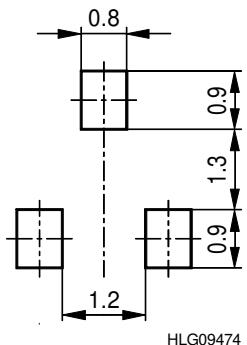
13 Avalanche characteristics
 $I_{AV} = f(t_{AV})$; $R_{GS} = 25 \Omega$

parameter: $T_{j(\text{start})}$

14 Typ. gate charge
 $V_{GS} = f(Q_{\text{gate}})$; $I_D = 3.7 \text{ A pulsed}$

parameter: V_{DD}

15 Drain-source breakdown voltage
 $V_{BR(DSS)} = f(T_j)$; $I_D = 250 \mu\text{A}$

16 Gate charge waveforms


PG-SC59
Package Outline:


GPS09473

Footprint:


HLG09474

Dimensions in mm

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